

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|-------|---|---|------------------|---------|------------------|
| | | ((test\$ near memory) (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 17:12 |
| S1 | 11768 | test\$3 near memory | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 14:02 |
| S2 | 55309 | test\$3 with memory | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 14:02 |
| S3 | 36 | (test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 14:18 |
| S4 | 8 | (test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 near circuit)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 16:59 |
| S5 | 0 | ((BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/738.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 17:10 |

| | | | | | | |
|-----|------|---|---|----|-----|------------------|
| S6 | 1 | ((BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/733.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 17:10 |
| S7 | 2 | ((BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 17:10 |
| S8 | 36 | (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 17:10 |
| S9 | 52 | ((test\$3 near memory) (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 17:12 |
| S10 | 10 | ("4754215", "4862460", "5214654", "5314492", "5739778").pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/04/21 18:01 |
| S11 | 2 | "6065145".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/11/17 16:52 |
| S12 | 1256 | clock near align\$5 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/11/17 16:52 |

| | | | | | | |
|-----|------|---|---|----|----|------------------|
| S13 | 1370 | clock near align\$5 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/11/17 16:52 |
| S14 | 9 | (clock near align\$5) and (delay near test\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/11/17 16:53 |